

1 **Supplementary Information**

2 **Investigation into the adhesion properties of PFAS on model**
3 **surfaces**

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5 *RSC Applied Interfaces*

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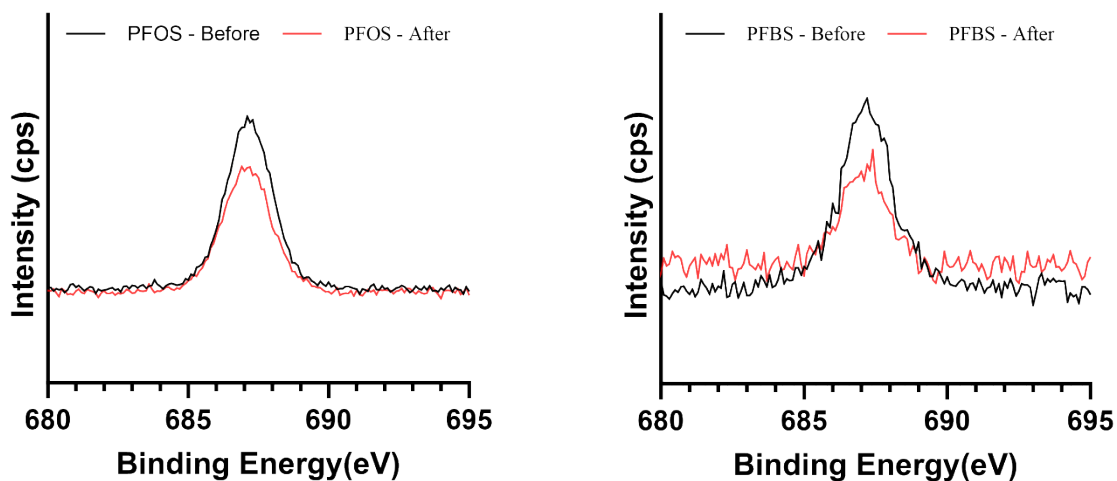


Figure S1. Confirmation of fluorine presence on PFOS and PFBS coated AFM tips. XPS scans for fluorine at 698eV for PFOS (left) and PFBS (right).

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Table S1. Contact angle and roughness values of modified wafers.

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<i>Sample</i>	<i>Contact Angle [°] (N = 10)</i>	<i>Roughness [nm] (N=3)</i>
<i>Plasma</i>	<5	0.327 ± 0.056
<i>APTES</i>	64.55 ± 2.46	0.250 ± 0.041
<i>C8</i>	104.52 ± 1.98	0.625 ± 0.073
<i>C18</i>	109.87 ± 2.44	0.313 ± 0.059